

L Number	Hits	Search Text	DB	Time stamp
1	1495	(c23c016\$.ipc. h011021\$.ipc. c23f01\$.ipc.) and (control\$4 same (transfer\$4 transport\$3) same (inspect\$3 observ\$5 test\$3 measur\$3 detect\$3))	EPO; JPO; DERWENT	2004/01/20 16:39
2	734	(c23c016\$.ipc. h011021\$.ipc. c23f01\$.ipc.) and (control\$4 with (transfer\$4 transport\$3) with (inspect\$3 observ\$5 test\$3 measur\$3 detect\$3))	EPO; JPO; DERWENT	2004/01/20 16:39
3	206	(c23c016\$.ipc. h011021\$.ipc. c23f01\$.ipc.) and (control\$4 same (transfer\$4 transport\$3) same (inspect\$3 observ\$5 test\$3 measur\$3 detect\$3) same ((set group plurality part portion fraction) with (wafer substrate)))	EPO; JPO; DERWENT	2004/01/20 17:07
4	0	156/345.124	USPAT; US-PGPUB	2004/01/20 17:08
6	90	(156/345.24.ccls. 156/345.15.ccls.) and (control\$4 same (transfer\$4 transport\$3))	USPAT; US-PGPUB	2004/01/20 17:09
5	9	(156/345.24.ccls. 156/345.15.ccls.) and (control\$4 same (transfer\$4 transport\$3) same (inspect\$3 observ\$5 test\$3 measur\$3 detect\$3) same ((set group plurality part portion fraction) with (wafer substrate)))	USPAT; US-PGPUB	2004/01/20 17:10
7	33	(156/345.24.ccls. 156/345.15.ccls.) and (control\$4 same (transfer\$4 transport\$3) same (inspect\$3 observ\$5 test\$3 measur\$3 detect\$3))	USPAT; US-PGPUB	2004/01/20 17:10
-	79	(US-5963753-\$ or US-5417537-\$ or US-5405230-\$ or US-6503365-\$ or US-6473151-\$ or US-6439822-\$ or US-6377329-\$ or US-6391114-\$ or US-5286296-\$ or US-6328768-\$ or US-6270619-\$ or US-6251191-\$ or US-6235171-\$ or US-6183564-\$ or US-6168667-\$ or US-4981408-\$ or US-4927484-\$ or US-6467491-\$ or US-6051101-\$ or US-5788868-\$ or US-6511315-\$ or US-6464789-\$ or US-6299363-\$ or US-6253118-\$ or US-6224274-\$ or US-6099643-\$).did. or (US-6024502-\$ or US-5820679-\$ or US-5769952-\$ or US-5766360-\$ or US-5695564-\$ or US-5937223-\$ or US-5733024-\$ or US-5639301-\$ or US-5626675-\$ or US-5571325-\$ or US-5565034-\$ or US-5544421-\$ or US-5430271-\$ or US-5061144-\$ or US-4787800-\$ or US-6402400-\$ or US-5974682-\$ or US-5942013-\$ or US-5826129-\$ or US-5725664-\$ or US-6402401-\$ or US-6074154-\$ or US-5803932-\$ or US-4985722-\$ or US-6313903-\$ or US-6379056-\$ or US-6290405-\$).did. or (US-6240874-\$ or US-6544338-\$ or US-6515731-\$ or US-6341903-\$ or US-6322119-\$ or US-6293713-\$ or US-6267516-\$ or US-6264705-\$ or US-6264381-\$ or US-6245156-\$ or US-6215545-\$ or US-6002108-\$ or US-5915396-\$ or US-5766824-\$ or US-5668733-\$ or US-5664254-\$ or US-5651823-\$ or US-5442416-\$ or US-5202716-\$).did. or (US-20030019578-\$ or US-20020189758-\$ or US-20020137346-\$ or US-20010008174-\$ or US-20020197878-\$ or US-20020092368-\$ or US-20020009658-\$).did. or (JP-2002184706-\$).did. or (EP-1184895-\$).did.	USPAT; US-PGPUB	2003/06/05 12:05

-	14	((US-5963753-\$ or US-5417537-\$ or US-5405230-\$ or US-6503365-\$ or US-6473151-\$ or US-6439822-\$ or US-6377329-\$ or US-6391114-\$ or US-5286296-\$ or US-6328768-\$ or US-6270619-\$ or US-6251191-\$ or US-6235171-\$ or US-6183564-\$ or US-6168667-\$ or US-4981408-\$ or US-4927484-\$ or US-6467491-\$ or US-6051101-\$ or US-5788868-\$ or US-6511315-\$ or US-6464789-\$ or US-6299363-\$ or US-6253118-\$ or US-6224274-\$ or US-6099643-\$).did. or (US-6024502-\$ or US-5820679-\$ or US-5769952-\$ or US-5766360-\$ or US-5695564-\$ or US-5937223-\$ or US-5733024-\$ or US-5639301-\$ or US-5626675-\$ or US-5571325-\$ or US-5565034-\$ or US-5544421-\$ or US-5430271-\$ or US-5061144-\$ or US-4787800-\$ or US-6402400-\$ or US-5974682-\$ or US-5942013-\$ or US-5826129-\$ or US-5725664-\$ or US-6402401-\$ or US-6074154-\$ or US-5803932-\$ or US-4985722-\$ or US-6313903-\$ or US-6379056-\$ or US-6290405-\$).did. or (US-6240874-\$ or US-6544338-\$ or US-6515731-\$ or US-6341903-\$ or US-6322119-\$ or US-6293713-\$ or US-6267516-\$ or US-6264705-\$ or US-6264381-\$ or US-6245156-\$ or US-6215545-\$ or US-6002108-\$ or US-5915396-\$ or US-5766824-\$ or US-5668733-\$ or US-5664254-\$ or US-5651823-\$ or US-5442416-\$ or US-5202716-\$).did. or (US-20030019578-\$ or US-20020189758-\$ or US-20020137346-\$ or US-20010008174-\$ or US-20020197878-\$ or US-20020092368-\$ or US-20020009658-\$).did. or (JP-2002184706-\$).did. or (EP-1184895-\$).did.) and (inspect\$3 ("5256204").PN.	USPAT; US-PGPUB	2003/06/05 12:05
-	1		USPAT; US-PGPUB	2003/06/05 16:44
-	1836	((118/719) or (414/939) or (156/345.31) or (156/345.32)).CCLS.	USPAT; US-PGPUB	2004/01/14 13:45
-	13	((118/719) or (414/939) or (156/345.31) or (156/345.32)).CCLS.) and (inspect\$3 with sampl\$3)	USPAT; US-PGPUB	2004/01/14 13:45
-	3	c23c016\$.ipc. and (inspect\$3 with sampl\$3)	EPO; JPO; DERWENT	2004/01/14 13:45
-	555	(427/\$.ccls. 438/\$.ccls. 216/\$.ccls.) and (inspect\$3 with sampl\$3)	USPAT; US-PGPUB	2004/01/14 13:46
-	122	(427/\$.ccls. 438/\$.ccls. 216/\$.ccls.) and ((inspect\$3 with sampl\$3) with (wafer substrate))	USPAT; US-PGPUB	2004/01/14 13:47
-	46	(427/\$.ccls. 438/\$.ccls. 216/\$.ccls.) and ((inspect\$3 with sampl\$3) with (control\$3 program\$3 procedur\$3 instruct\$3 computer\$4))	USPAT; US-PGPUB	2004/01/14 13:49
-	46	(427/\$.ccls. 438/\$.ccls. 216/\$.ccls.) and ((inspect\$3 with sampl\$3) with (control\$3 program\$3 procedur\$3 instruct\$4 computer\$4))	USPAT; US-PGPUB	2004/01/14 14:02
-	2	((118/719) or (414/939) or (156/345.31) or (156/345.32)).CCLS.) and ((inspect\$3 with sampl\$3) with (control\$3 program\$3 procedur\$3 instruct\$4 computer\$4))	USPAT; US-PGPUB	2004/01/14 14:03
-	107	((inspect\$3 with sampl\$3) with (control\$3 program\$3 procedur\$3 instruct\$4 computer\$4) with (wafer substrate semiconductor))	USPAT; US-PGPUB	2004/01/14 15:36

-	6	6208751.URPN.	USPAT	2004/01/14 15:13
-	4	("4618938" "4764969" "5614837" "5699447").PN.	USPAT	2004/01/14 15:15
-	13	(inspect\$3 measur\$3 observ\$3 detect\$3) with sampl\$3 with (control\$3 program\$3 procedur\$3 instruct\$4 computer\$4) with (wafer substrate semiconductor) with (one single each) with (set group)	USPAT; US-PGPUB	2004/01/14 15:53
-	4	(inspect\$3 measur\$3 observ\$3 detect\$3) with sampl\$3 with (control\$3 program\$3 procedur\$3 instruct\$4 computer\$4) with (wafer substrate semiconductor) with (one single each) with (set group)	EPO; JPO; DERWENT	2004/01/14 15:54
-	5	(inspect\$3 measur\$3 observ\$3 detect\$3) with sampl\$3 with (control\$3 program\$3 procedur\$3 instruct\$4 computer\$4) with (wafer substrate semiconductor) with (one single each) with (set group pluralit\$3)	EPO; JPO; DERWENT	2004/01/14 17:04
-	1	("5766360").PN.	USPAT; US-PGPUB	2004/01/14 17:05
-	1	("6593045").PN.	USPAT; US-PGPUB	2004/01/14 17:08
-	3	("5899690" "5915910" "6051349").PN.	USPAT	2004/01/14 17:05
-	146	inspect\$3 with coat\$3 with develop\$3	USPAT; US-PGPUB	2004/01/14 17:38
-	47	SHIGA-MASAYOSHI.in. HASHINOKI-KENJI.in. OHTANI-MASAMI.in. NISHIMURA-JOICHI.in.	USPAT; US-PGPUB	2004/01/20 16:29